

Editorial

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The *JETTA* Editorial Board meeting at Austin, Texas, November 3, 2009 was attended by (*l to r in photograph*) Xiaowei Li, Hans-Joachim Wunderlich, Peter Maxwell, Charles Glaser (Springer), Melvin Breuer, Sybille Hellebrand, Vishwani Agrawal, Patrick Girard, Kewal Saluja and John Hayes.

Our last mixed-signal test special issue was published in December 2007. In the intervening years two workshops have been held: IMS3TW'08, *International Mixed-Signals, Sensors and Systems Test Workshop*, June 2008, Vancouver, Canada, and IMS3TW'09, June 2009, Scottsdale, Arizona, USA. So, after a gap of two years we are pleased to bring you this special issue, for which Karim Arabi, the guest editor, deserves our deepest gratitude. He was responsible for the entire peer review process for these papers including

selecting and inviting reviewers, accepting and rejecting papers, and having the accepted papers revised in the form you see here. His guest editorial gives more details.

With this issue, we begin volume 26 of *JETTA*. Of the six issues, two will carry special themes. Besides mixed-signal test (this issue), we will have an issue devoted to “High-Level Design Validation and Test,” based on HLDVT 2009, *IEEE International High-Level Design, Validation and Test Workshop*, San Francisco, California, November 4–6, 2009. Prabhat Mishra will be the guest editor. We continue a special relationship with the *IEEE European Test Symposium* (ETS) through which selected papers from that symposium are submitted to *JETTA* and, if accepted by our peer review process, appear in regular issues.

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